

Correspondence

Planar Transmission Lines—II

I would like to call your attention to a certain mistake in the above paper.¹ Park's transmission line, consisting of two parallel strips between two wide plates [Fig. 1(a)], has to be changed to the line geometry indicated in Fig. 1(b) in order to maintain the results of the mentioned paper.

The mistake originates from a false interpretation of

$$jz' = \sqrt{k\rho} \operatorname{sn}(jKZ/H), \quad (6)$$

in particular of the elliptic function $\operatorname{sn} x$.

the rectangular box 3'-3-5-5' in contrast to the geometry given in the mentioned paper. The box is transformed into the imaginary axis of the z' plane which is a potential line of the configuration and therefore does not impair the field between the two circle electrodes 9-8-10 and 9'-8'-10'.

In order to check the validity of the statements made one can easily calculate the characteristic impedances of the open and enclosed parallel plate lines (Fig. 1) for the special case $H \rightarrow \infty$ and $C \gg D$. The impedance of the open line is found to be $Z_0' = 120\pi D/C$, and from the exact formu-

Rebuttal

I should like to thank Dr. Giger for pointing out this error—it was due to an uncritical use of somebody else's formula—and to express my regret that it should have occurred. It might be added that the problem which I have solved by inadvertence is one which arises naturally out of my first paper,² and (if there are no further errors) may possibly be of greater practical use than that whose solution Dr. Giger has criticized.

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² David Park, "Planar transmission lines," *TRANS. IRE*, vol. MTT-3, pp. 8-12; April, 1955.

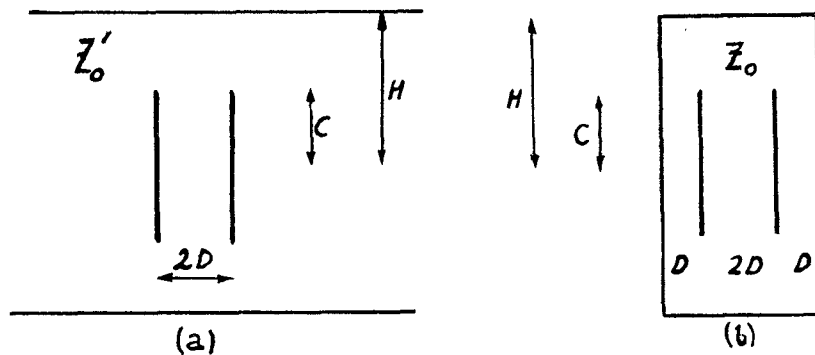


Fig. 1—(a) Open and (b) enclosed parallel plate lines.

Determination of the Parameters of Cavities Terminating Transmission Lines

The method of measuring cavity parameters outlined in the above paper¹ has been used successfully for some time by our laboratory for measuring parameters of cavities at X band having Q 's as high as 150,000. For improved accuracy in these measurements, an additional refinement has been made in the method which makes all measurements independent of the law of the crystal detectors used.

The method consists simply of inserting immediately after the signal generator, in Libowitz's circuits, a precision calibrated attenuator. This attenuator is used to refer all measurements to a fixed power level in the crystal. For example, in measuring loaded Q the 3 db point on the observed cavity absorption dip is determined by changing the attenuator 3 db. VSWR measurements of coupling parameters are taken in db from the attenuator and converted to other desired parameters by the scales on a Smith Chart. Such measurements are simplified further by use of a dc coupled oscilloscope.

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¹ R. A. Libowitz, *TRANS. IRE*, vol. MTT-4, pp. 51-53; January, 1956.

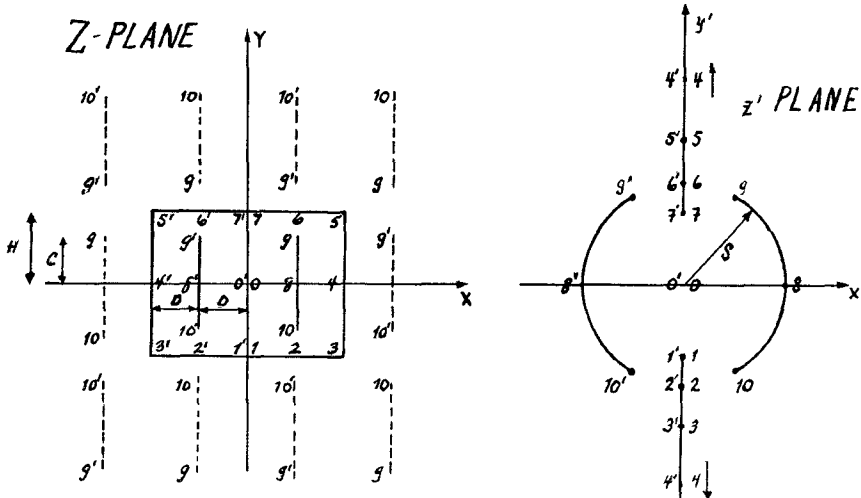


Fig. 2—Mapping of Z plane into z' plane by means of (6).

The correct mapping is shown in Fig. 2. One should note that $\operatorname{sn} x$ is a double periodic function. That is the reason why the two strips 9-10 and 9'-10' are actually within

las of Park one has $Z_0 = 60\pi D/C$ which is half the value of Z_0' and therefore corresponds to the configuration of Fig. 1(b).

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¹ D. Park, *TRANS. IRE*, vol. MTT-3, pp. 7-11; October, 1955.

A Low VSWR Matching Technique

A variation on the method described by Feller and Weidner¹ for obtaining low standing wave ratios over a frequency band has

¹ R. G. Fellers and R. T. Weidner, "Broad-band waveguide admittance matching by use of frises," *PROC. IRE*, vol. 35, pp. 1080-1085, October, 1947.